



May 1998

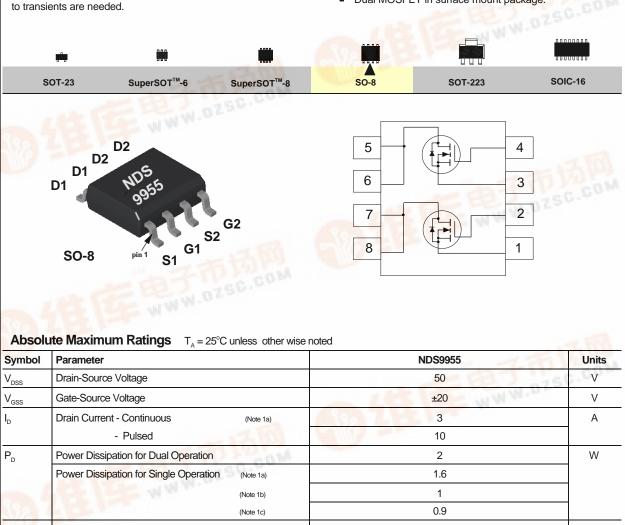
NDS9955 Dual N-Channel Enhancement Mode Field Effect Transistor

General Description

SO-8 N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, high cell density, DMOS technology. This very high density process is especially tailored to provide superior switching performance and minimize on-state resistance. These devices are particularly suited for low voltage applications such as disk drive motor control, battery powered circuits where fast switching, low in-line power loss, and resistance to transients are needed.

Features

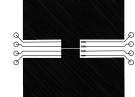
- 3.0 A, 50 V. $R_{DS(ON)} = 0.130 \Omega @ V_{GS} = 10 V$, $R_{DS(ON)} = 0.200 \Omega @ V_{GS} = 4.5 V$.
- High density cell design for extremely low R_{DS(ON)}.
- High power and current handling capability in a widely used surface mount package.
- Dual MOSFET in surface mount package.



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Symbol	Parameter	Conditions		Min	Тур	Max	Units
OFF CHAR	ACTERISTICS	·					
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 V, I_{D} = 250 \mu A$		50			V
$\Delta BV_{DSS} / \Delta T_{J}$	Breakdown Voltage Temp. Coefficient	$I_D = 250 \ \mu\text{A}$, Referenced to $25 \ ^{\circ}\text{C}$			60		mV/ °C
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 40 V, V_{GS} = 0 V$				2	μA
	Gate - Body Leakage, Forward	$V_{GS} = 20 \text{ V}, V_{DS} = 0 \text{ V}$				100	nA
I _{GSSR}	Gate - Body Leakage, Reverse	$V_{GS} = -20 V, V_{DS} = 0 V$				-100	nA
ON CHARA	CTERISTICS (Note 2)						
V _{GS(th)}	Gate Threshold Voltage $V_{DS} = V_{GS}$, $I_D = 250 \mu A$			1	1.7	3	V
			T _J =125°C	0.7		2.2	
R _{DS(ON)}	Static Drain-Source On-Resistance	$V_{GS} = 10 \text{ V}, \text{ I}_{D} = 3 \text{ A}$			0.076	0.13	Ω
			T _J =125°C		0.124	0.2	
		$V_{GS} = 4.5 \text{ V}, \ \text{I}_{D} = 1.5 \text{ A}$			0.103	0.2	
			T _J =125°C		0.166	0.3	
D(ON)	On-State Drain Current	$V_{GS} = 10 \text{ V}, V_{DS} = 10 \text{ V}$		10			А
9 _{FS}	Forward Transconductance	$V_{DS} = 10 \text{ V}, \text{ I}_{D} = 3 \text{ A}$			5.3		S
DYNAMIC (CH ARACTERISTICS						
C _{iss}	Input Capacitance	$\frac{V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},}{f = 1.0 \text{ MHz}}$			345		pF
C _{oss}	Output Capacitance				110		pF
C _{rss}	Reverse Transfer Capacitance				25		pF
SWITCHING	CHARACTERISTICS (Note 2)						
D(on)	Turn - On Delay Time	$V_{DS} = 25 \text{ V}, \text{ I}_{D} = 1 \text{ A}$	$V_{DS} = 25 \text{ V}, \text{ I}_{D} = 1 \text{ A}$		5	20	ns
r	Turn - On Rise Time	V_{GS} = 10 V , R _{GEN} = 6 Ω			7.5	20	
D(off)	Turn - Off Delay Time				20	70	
f	Turn - Off Fall Time				7	5	
Q _g	Total Gate Charge	$V_{DS} = 25 V, I_{D} = 2 A,$			12.9	30	nC
Q _{gs}	Gate-Source Charge	V _{GS} = 10 V			1.7		
ସ _{gd}	Gate-Drain Charge				3.2		
DRAIN-SOU	RCE DIODE CHARACTERISTICS AND MA	XIMUM RATINGS					
S	Maximum Continuous Drain-Source Diode F	Forward Current				1.3	А
V _{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0 V, I_{S} = 1.3 A$ (Note 2)			0.8	1.2	V
Tr	Reverse Recovery Time	$V_{GS} = 0 V$, $I_F = 1.3 A$, $dI_F/dt = 100 A/\mu s$			40		ns
m	Reverse Recovery Current				1.5	-	А

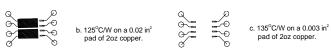
1. $R_{\mu\nu}$ is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. $R_{\mu\nu}$ is guaranteed by design while R_{\thetacA} is determined by the user's board design.



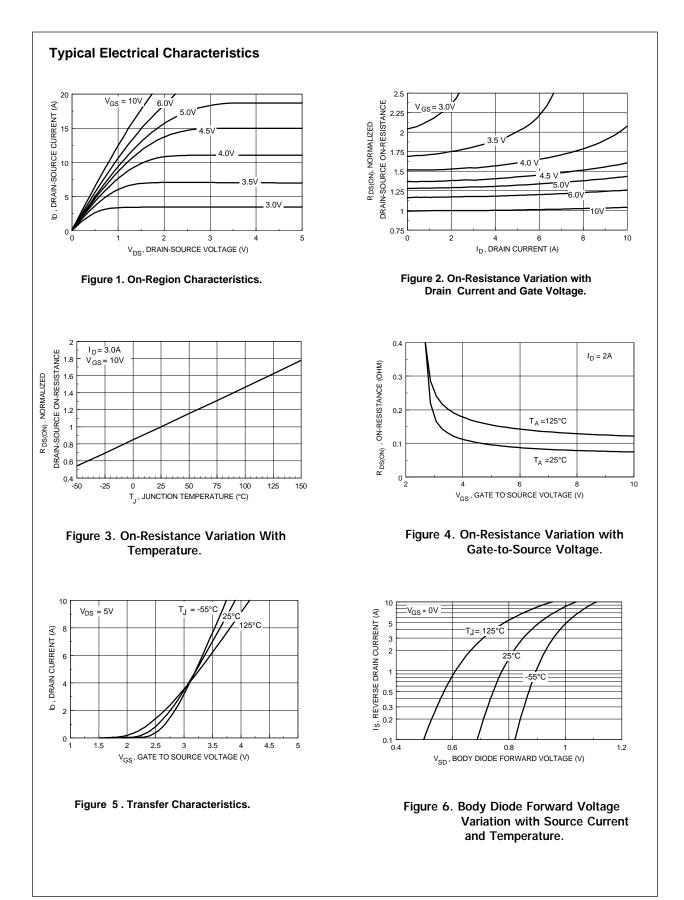
a. 78°C/W on a 0.5 in² pad of 2oz copper.

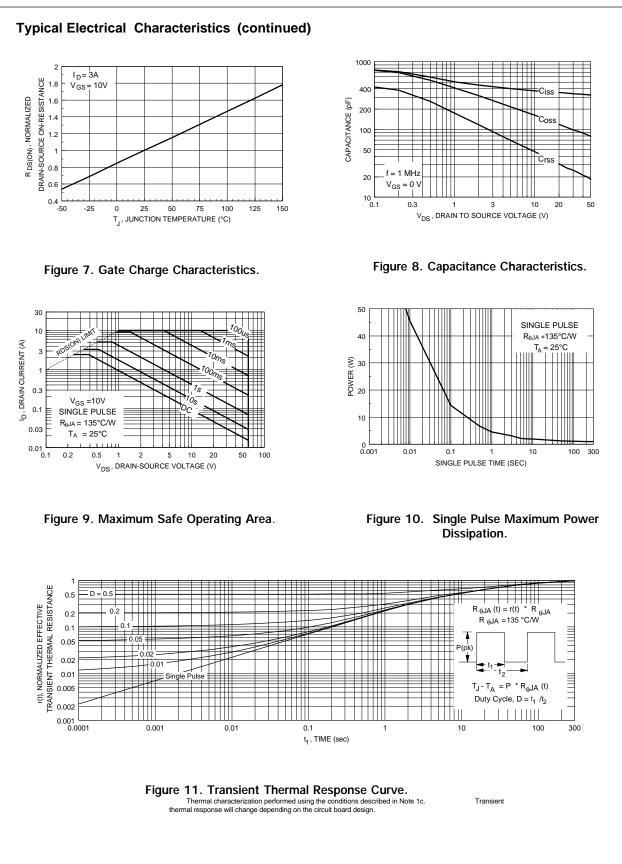
Scale 1 : 1 on letter size paper

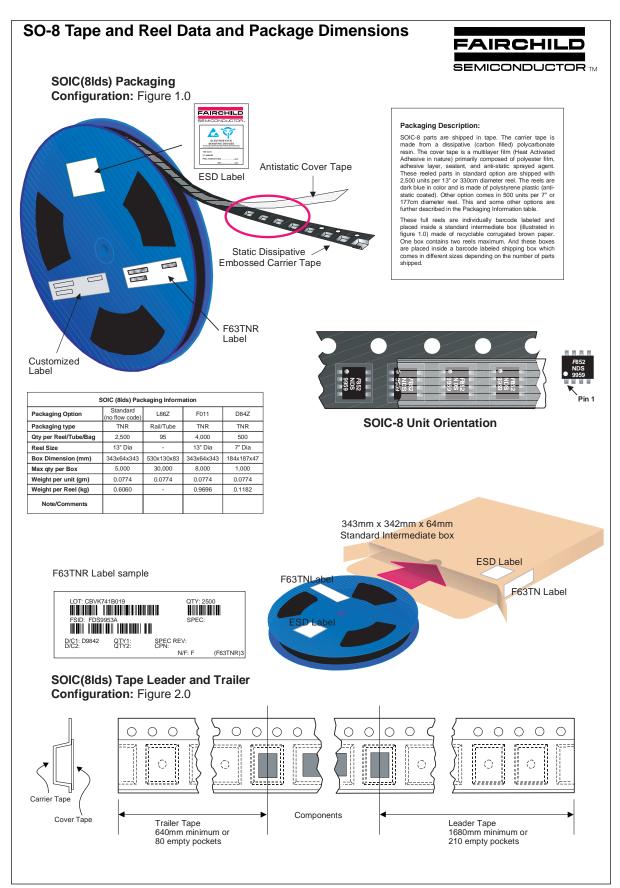


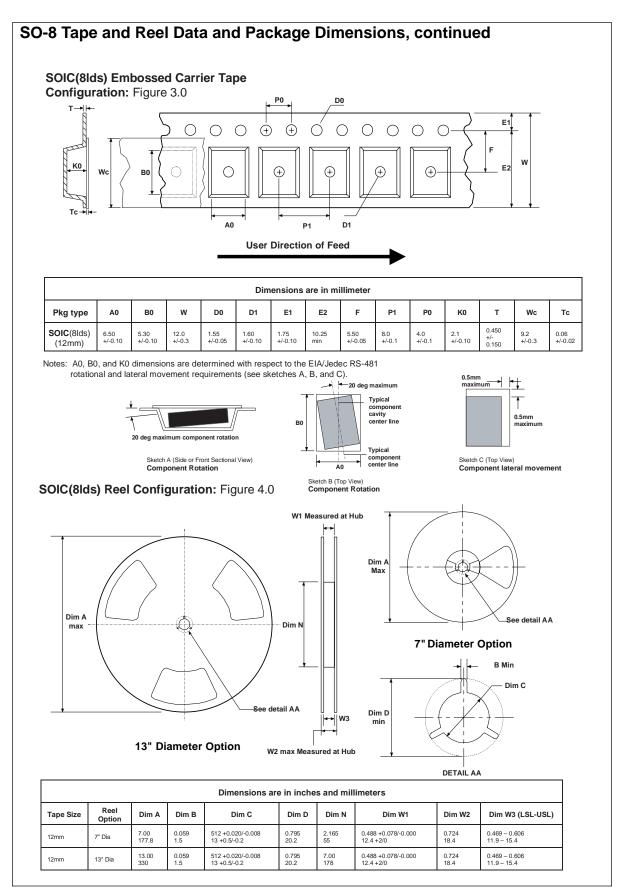


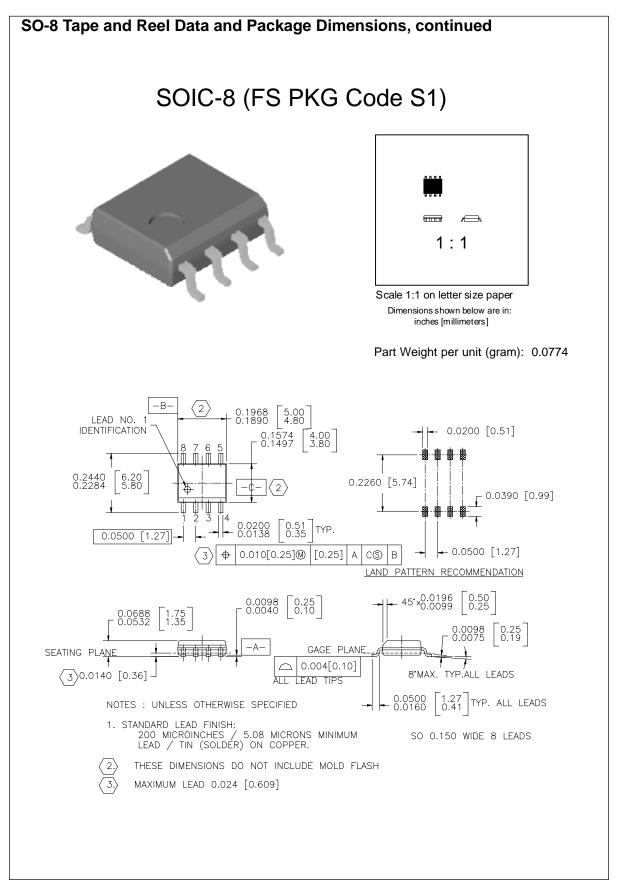
2. Pulse Test: Pulse Width \leq 300µs, Duty Cycle \leq 2.0%.











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